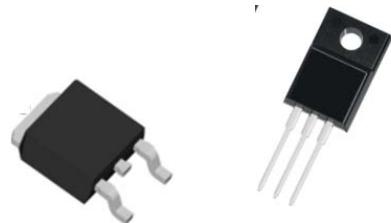


## 650V 11A Power MOSFET

### ■ Description

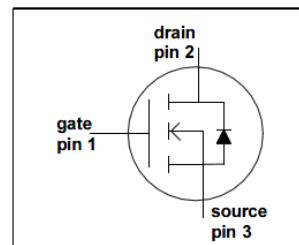
XCH Semiconductor(XCH) has series Multi-EPI Super-Junction power MOSFET platforms for voltage up to 500V to 1000 volts, both with design service and manufacturing capability, including cell, termination design and simulation.

The GSx11N65E is a Low voltage N channel Multi-EPI Super-Junction power MOSFET sample with advanced technology to have better characteristics, such as fast switching time, low C<sub>iss</sub> and C<sub>rss</sub>, low on resistance and excellent avalanche characteristics.



TO-252

TO-220F



### ■ Features

RDS(ON)=0.42Ω @ VGS = 10V

VDS = 650V

### ■ PKG

GSA11N65E	GSD11N65E
TO-220F	TO-252

### ■ Absolute Maximum Ratings (TC = 25°C, unless otherwise specified)

Symbol	Parameter	GSA11N65E	GSD11N65E	Unit
V <sub>DSS</sub>	Drain-Source Voltage		650	V
I <sub>D</sub>	Drain Current - Continuous (TC = 25°C) - Continuous (TC = 100°C)		11* 7*	A
I <sub>DM</sub>	Drain Current - Pulsed		42	A
V <sub>GSS</sub>	Gate-Source voltage		±30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy		260	mJ
I <sub>AR</sub>	Avalanche Current		2	A
E <sub>AR</sub>	Repetitive Avalanche Energy		1	mJ
dv/dt	Peak Diode Recovery dv/dt		15	V/ns
dVds/dt	Drain Source voltage slope (Vds=480V)		50	V/ns
P <sub>D</sub>	Power Dissipation (TC = 25°C)	31	96	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Max. Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C

### ■ Thermal Characteristics

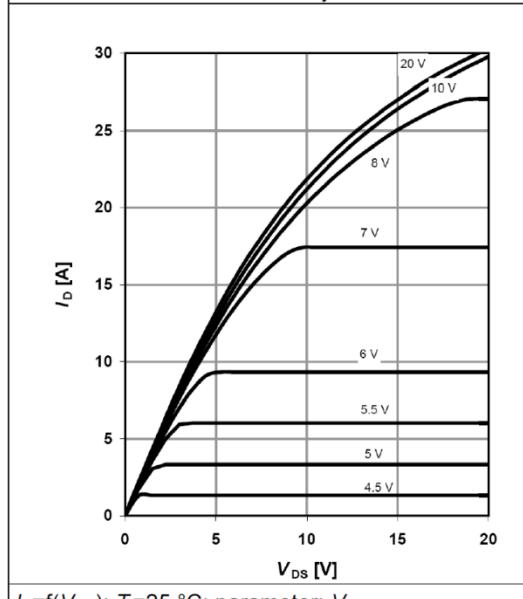
Symbol	Parameter	GSA11N65E	GSD11N65E	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	4.0	1.3	°C/W
R <sub>θCS</sub>	Thermal Resistance, Case-to-Sink Typ.	--	0.5	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	80	62	°C/W

## ■ Electrical Characteristics (TJ=25° C unless otherwise specified)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA, T <sub>J</sub> = 25°C	650	--	--	V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA, T <sub>J</sub> = 150°C	--	700	--	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	--	0.6	--	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>D</sub> S = 650V, V <sub>GS</sub> = 0V -T <sub>J</sub> = 150°C	--	10	1	μA μA
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30V, V <sub>D</sub> S = 0V	--	--	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30V, V <sub>D</sub> S = 0V	--	--	-100	nA
<b>On Characteristics</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>D</sub> S = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5	--	4.5	V
R <sub>D(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.5A	--	0.38	0.42	Ω
g <sub>F</sub> S	Forward Transconductance	V <sub>D</sub> S = 40V, I <sub>D</sub> = 5.5A	--	16	--	S
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>D</sub> S = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	--	720	-	pF
C <sub>oss</sub>	Output Capacitance		--	20	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		--	1.5	--	pF
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>D</sub> D = 400V, I <sub>D</sub> = 5.5A RG = 20Ω (Note 4)	--	15	--	ns
t <sub>r</sub>	Turn-On Rise Time		--	10	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	110	--	ns
t <sub>f</sub>	Turn-Off Fall Time		--	9	--	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>D</sub> S = 400V, I <sub>D</sub> = 5.5A V <sub>GS</sub> = 10V (Note 4)	--	32	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	4	--	nC
Q <sub>gd</sub>	Gate-Drain Charge		--	16	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current	--	--	9.2	A	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current	--	--	30	A	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 5.5A	--	0.9	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 5.5A dI/dt = 100A/μs	--	280	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	3.3	--	μC

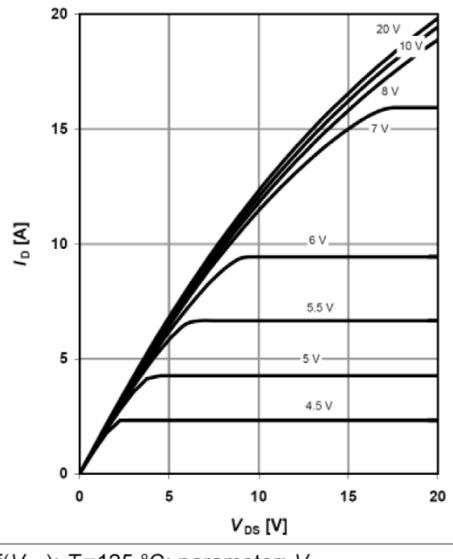
## Typical Performance Characteristics

Typ. output characteristics  $T_J=25\text{ }^\circ\text{C}$



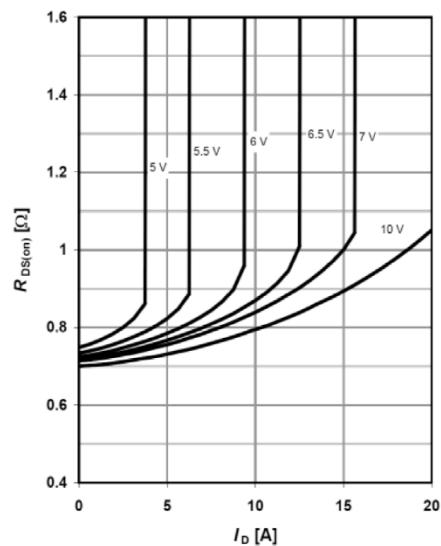
$I_D=f(V_{DS})$ ;  $T_J=25\text{ }^\circ\text{C}$ ; parameter:  $V_{GS}$

Typ. output characteristics  $T_J=125\text{ }^\circ\text{C}$



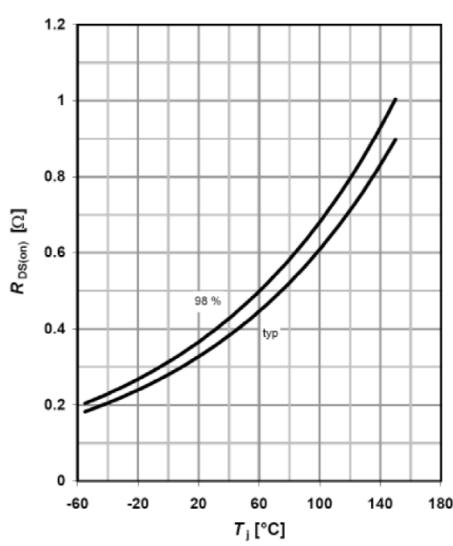
$I_D=f(V_{DS})$ ;  $T_J=125\text{ }^\circ\text{C}$ ; parameter:  $V_{GS}$

Typ. drain-source on-state resistance



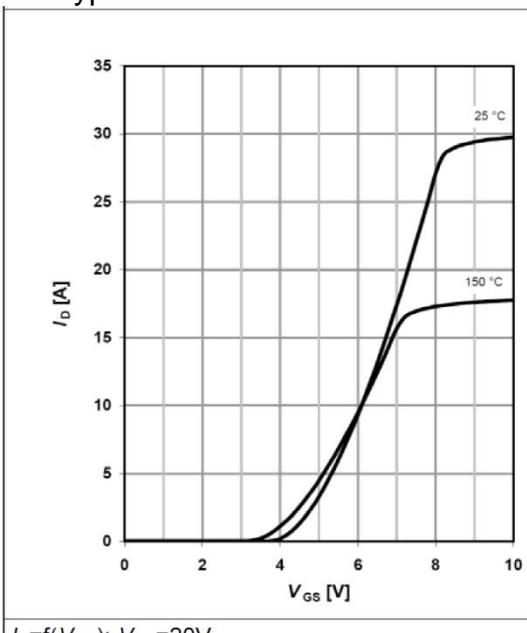
$R_{DS(on)}=f(I_D)$ ;  $T_J=125\text{ }^\circ\text{C}$ ; parameter:  $V_{GS}$

Typ. drain-source on-state resistance



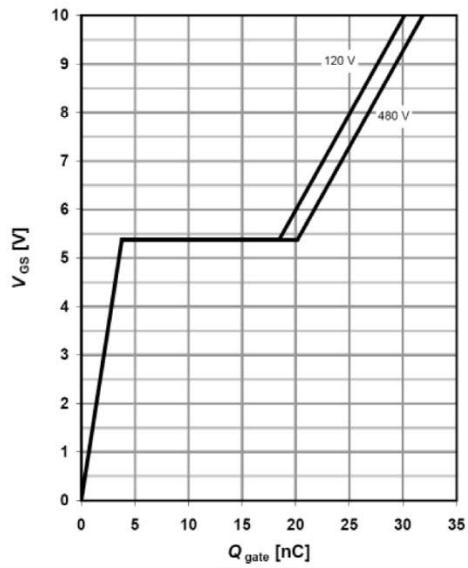
$R_{DS(on)}=f(T_J)$ ;  $I_D=3.8\text{ A}$ ;  $V_{GS}=10\text{ V}$

Typ. transfer characteristics



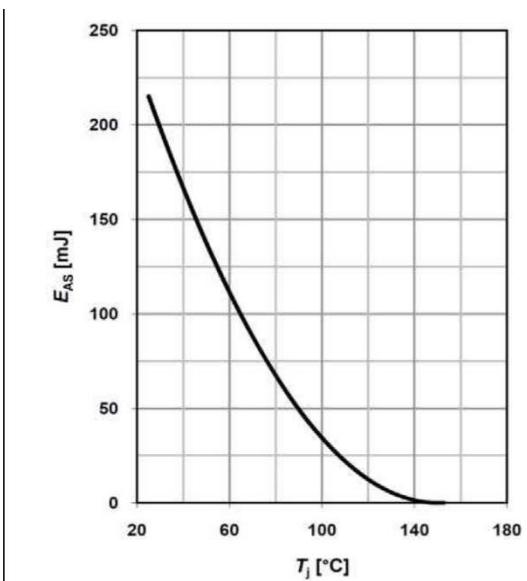
$I_D=f(V_{GS})$ ;  $V_{DS}=20\text{ V}$

Typ. gate charge



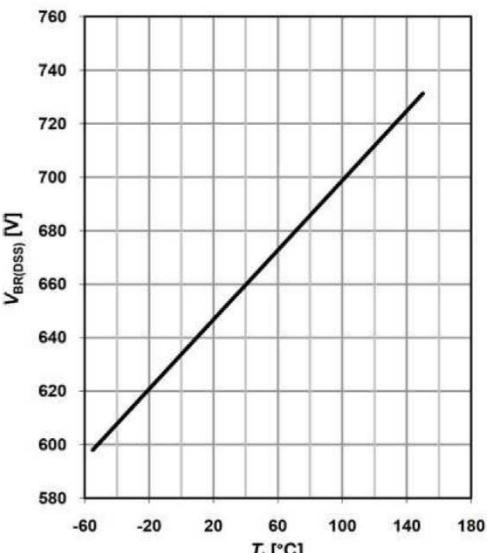
$V_{GS}=f(Q_{gate})$ ,  $I_D=4.8\text{ A}$  pulsed

Avalanche energy



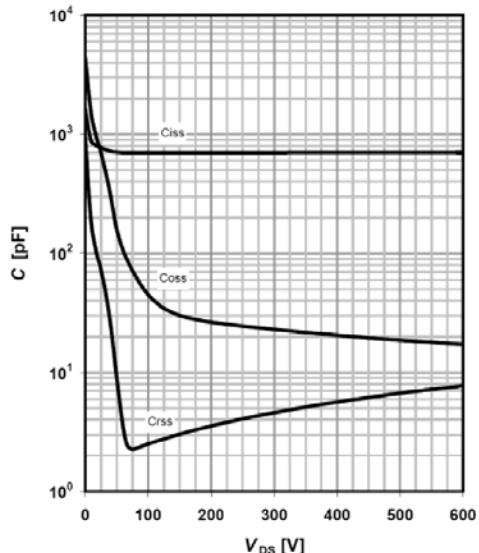
$E_{AS}=f(T_j)$ ;  $I_D=1.8\text{ A}$ ;  $V_{DD}=50\text{ V}$

Drain-source breakdown voltage



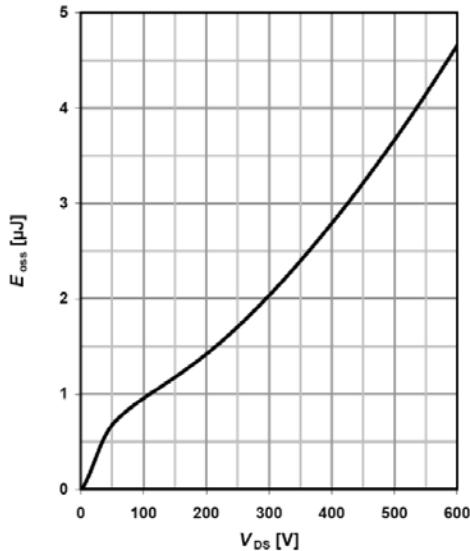
$V_{BR(DSS)}=f(T_j)$ ;  $I_D=1.0\text{ mA}$

Typ. capacitances



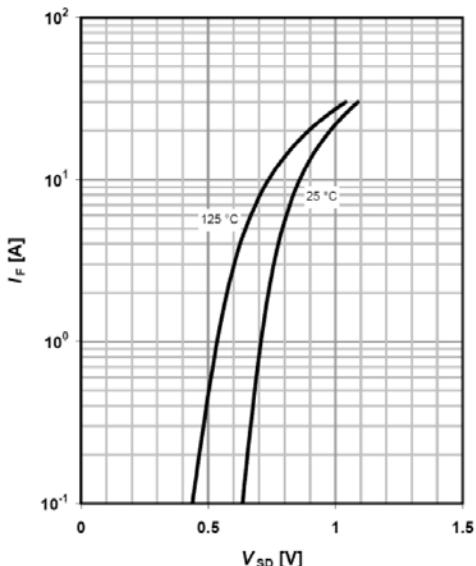
$C=f(V_{DS})$ ;  $V_{GS}=0$  V;  $f=1$  MHz

Typ. Coss stored energy



$E_{oss}=f(V_{DS})$

Forward characteristics of reverse diode



$I_F=f(V_{SD})$ ; parameter:  $T_j$